

# Open Meeting About US ATLAS Liquid Argon (LAr) Calorimeter Phase II Upgrade Planning

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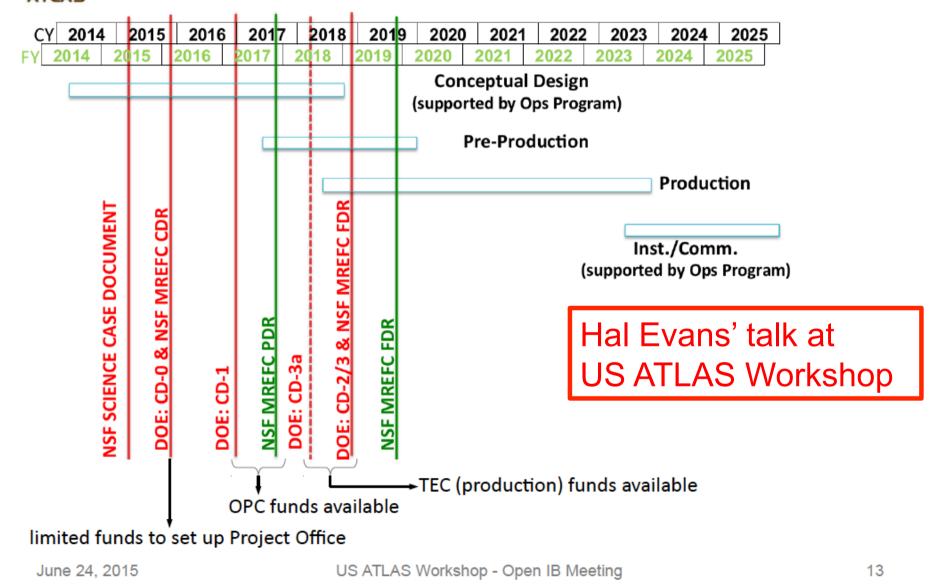
# LAr Phase-II Organization

- ❖ Modest US R&D funding supporting sFCAL effort as well as ASIC design for frontend electronics
- JP appointed in Jan. as LAr Phase II construction manager
- ❖ US ATLAS working toward preparing DoE and NSF proposals for Phase II construction project
  - Need to define scope, institutional responsibilities, cost and manpower, ...
  - Draft WBS, planning etc. being worked on

Name	6.3 LAr: V	6.3 LAr: WBS DICTIONARY		
G.3.1   FCAL				
6.3.1.1.1         FCAL Mechanics         Arizona           6.3.1.1.2         FCAL Mechanics Iowa         Iowa           6.3.1.2         FCAL Cold Electronics         Arizona           6.3.2.1         Frontend Electronics         Arizona           6.3.2.1         Preamp/shaper         BNL           6.3.2.1.1         Preamp/shaper BNL         BNL           6.3.2.1.2         Preamp/shaper UPenn         UPenn           6.3.2.2.1         ADC/Gain Selector         Nevis           6.3.2.2.2         ADC/Gain Selector UTD         UTDallas           6.3.2.3.3         Optical links         Nevis           6.3.2.3.1.         ADC/Link Interface         Nevis           6.3.2.3.1.2         ADC/Link Interface Nevis         Nevis           6.3.2.3.1.2         ADC/Link Interface SMU         SMU           6.3.2.3.2.2         Electrical components         SMU           6.3.2.3.2.3         Optical components         SMU           6.3.2.4.1         FEB2 System Integration         FEB2 System Integration           6.3.2.4.2         FEB2 System Integration Nevis         Nevis           6.3.2.5.5         FEB2 PCB         Nevis           6.3.2.6.1         Radiation qualification and testing         Nevis	WBS	Name	Institute	
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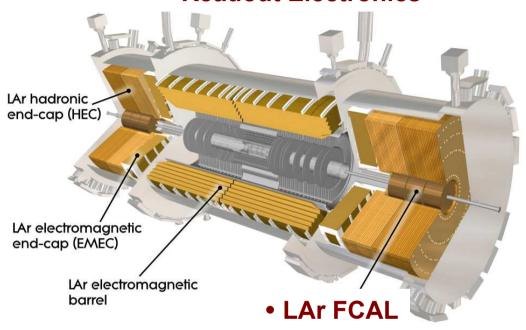
# U.S. Funding/Review Schedule





# LAr Phase II Upgrade Project

#### Readout Electronics



### ATLAS LAr Phase II Upgrade:

- Replace the LAr readout electronics
- Modify the forward region, including:
  - possible new (s)FCAL (or miniFCAL)
  - possible new forward precision timing detector



# **FCAL**



# **LAr Detector Options in Lol**

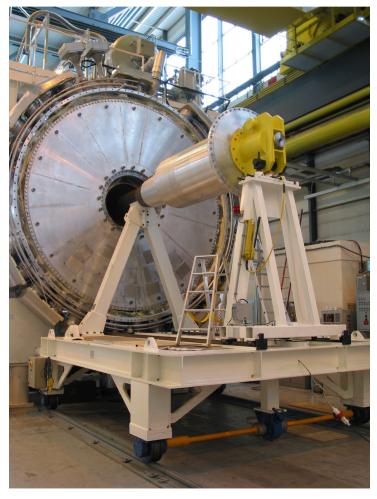
- Option 0: No change neither of the HEC cold electronics nor of the FCal detectors.
- Option 1: If the HEC cold electronics have to be replaced (Sec. 3.2.2), the large cold cryostat cover would have to be opened and the irradiated FCal would have to be removed. A newly built cold FCal (sFCal) (Sec. 3.2.3) would then be inserted before closing the cryostat.
- Option 2: If the HEC cold electronics do not have to be replaced, the cold FCal would be replaced by a new one of the sFCal type (Sec. 3.2.3). It is anticipated that only the small cover of the cold vessel, the FCal bulkhead, would have to be removed.
- Option 3: If the HEC cold electronics do not have to be replaced, the cold FCal would stay
  in place and a new small calorimeter (Mini-FCal) (Sec. 3.2.4) would be placed in front of it.
  In this case only the cryostat warm vessel would have to be opened.



# **Endcap Cryostat**

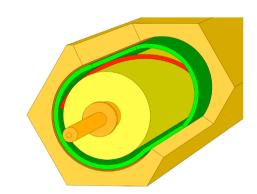
• HEC cold electronics do not need to be replaced, so there is no need to remove the large cold cover (means FCAL summing boards not accessible)

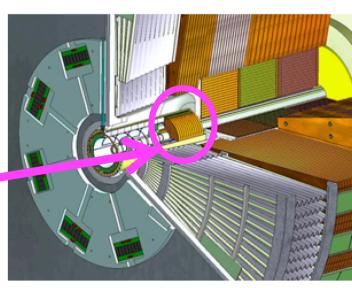




# Forward Calorimeter

- ❖ ATLAS EM and hadronic calorimeter detectors are able to cope with HL-LHC conditions
- Only exception is ATLAS FCAL, which uses novel (US) design with absorber rods housed in absorber lattice, and small LAr gaps (270 – 500 μm)
- ❖ Beyond design luminosity, enormous rates lead to space charge problems (even possibly boiling of LAr), as well as voltage drops across HV resistors
  - Utilizing the same design concept but with thinner gaps (down to 100 μm), one could tolerate the HL-LHC conditions
  - Using this technique, solutions being investigated include:
    - A new calorimeter ("sFCAL"), or
    - A "Mini-FCAL"(placed in front of the existing FCAL)



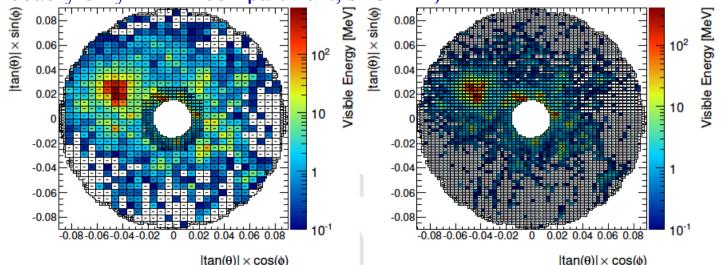




# FCAL (cont'd)

- \* Recent simulations suggest LAr will not boil (though margin is small)
  - However, geometry is complicated and difficult to simulate accurately
  - A mockup has been built, but testing is so far inconclusive
  - Further LAr sub-cooling by  $\Delta T$ = -1.6 K successfully tested during recent shutdown (and  $\Delta T$ = -2 K is believed to be possible)
- ❖ FCAL performance issues have been discussed by large-eta task force (LETF)
  - Gets tied in with fwd tracking, possible new timing and/or "preshower-type" detector in space previously occupied by MBTS, etc. (see later)

 Suggestion has also been made to increase readout granularity in case of sFCAL (probably only in EM-compartment, sFCAL1)





### **FCAL Decision**

- Decision of final approach still to be made
  - Originally scheduled for March 2015
  - Pushed back, with review now scheduled for December 2015 (any later could jeopardize readiness of sFCAL for when it is needed for installation)
  - Continuing to work on multiple fronts, to prepare decision:
    - Finalize understanding of whether LAr boiling will occur if no change is made in the forward region
    - Explore performance, and associated physics impact, of various scenarios (degraded FCAL, sFCAL with low/high granularity, miniFCAL)
      - VERY limited (physicist) manpower available
    - Work to solve engineering issues related to realization of miniFCAL concept
- Until final decision, need to carry options



# **Readout Electronics**

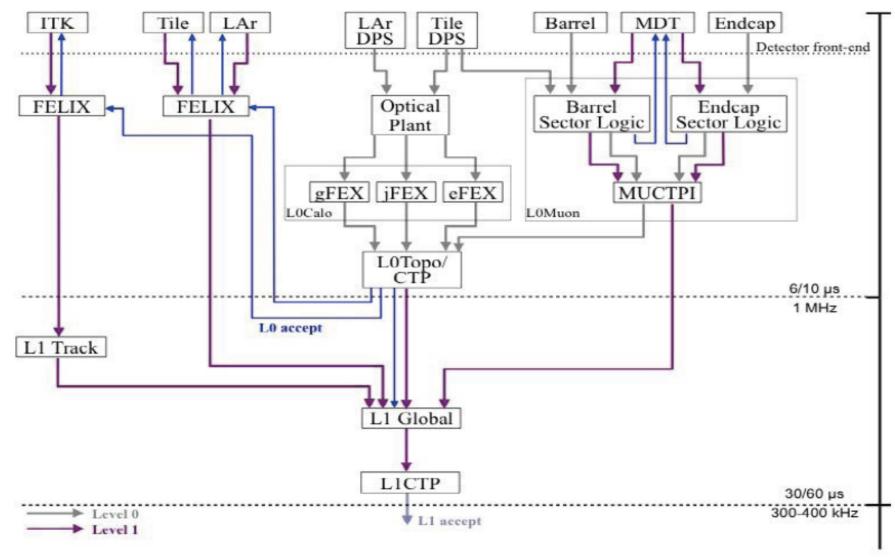


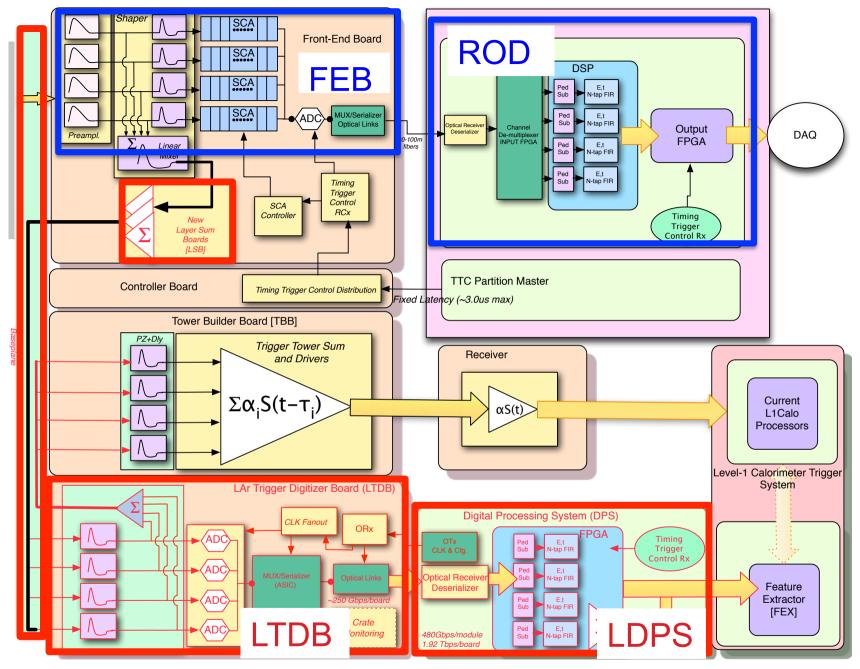
### **New LAr Readout Electronics**

- ❖ To adapt to Phase II TDAQ architecture, need to replace LAr readout
  - Current readout would continue to limit L1 rate to 100 kHz, and latency to  $\sim 2.5 \,\mu s$
- Plan to develop new "FEB2", digitizing and sending off detector all channels at 40 MHz
  - Move pipeline off detector, out of radiation environment
  - Have full granularity calo. info available for new L1 trigger, so that shower shape info, etc. can be used to allow EM trigger thresholds to remain low
  - Use Phase I LAr trigger upgrade electronics as part of new LO trigger used to seed
     Phase II L1 track trigger
- ❖ Will also need new backend electronics to receive and process the FEB2 data (boundaries between LAr and TDAQ become more blurry, certainly for L1)



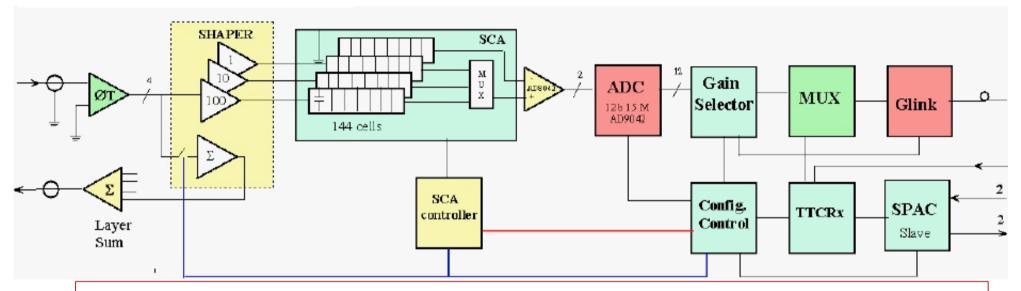
# Phase II TDAQ Architecture



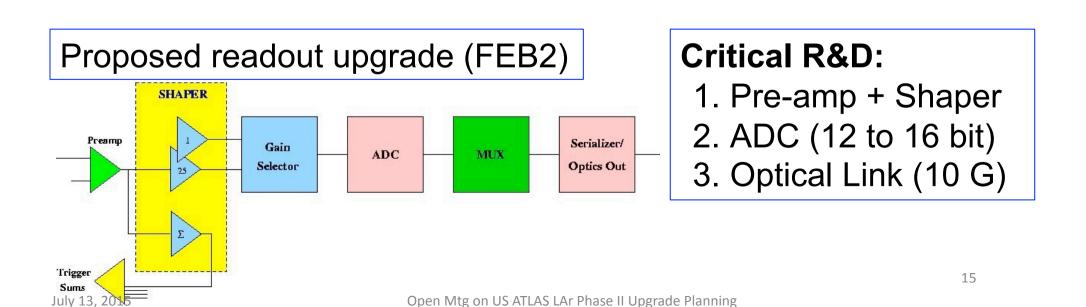


Red for Phase I. Blue for Phase II.

### The front-end:



Current detector readout scheme on the (US-designed) FEB





# **LAr FE Electronics Developments**

- \* Main goal of current R&D is the investigation of the potential of 65 nm CMOS to meet the various needs for FEB2 ASICs:
  - Preamp/shaper ASIC
    - Prototyped originally in SiGe (UPenn/BNL)
    - New BNL effort on 65 nm CMOS, with major challenge being 16-bit dynamic range
    - By fall, Upenn will shift focus to help with 65 nm investigation

#### ADC

- 130 nm ADC (pipeline + SAR) developed at Columbia is nearing production phase for use in Phase I, and design effort has turned to 65 nm for Phase II
- o Formed new collaboration with UT Dallas, who is focusing (on all-SAR version) in 65 nm
- Optical links
  - Need ~100 Gpbs of rad-tol optical link bandwidth per 128-channel FEB2
  - SMU working on serializer/driver for ~ 10 Gbps optical link, as well as optical components (as part of Versatile Link project)
- ❖ In ~1 year, should have enough experience (and even first prototypes) to gauge potential to use 65 nm as a common technology for the various blocks
  - Later step would see whether further ASIC consolidation would be possible/desirable



### **LAr BE Electronics**

- Readout of FEB2 will require new backend electronics
- Full granularity data will be used for both precision readout (eg. in offline analysis) as well as for triggering at L1 and above
  - Boundaries between LAr and TDAQ subsystems become more blurry
- ❖ A lot to be learned from the Phase I LAr trigger upgrade, where the LDPS will receive and process data from "super-cells" at 40 MHz
- ❖ BE construction responsibilities for Phase II are so far less advanced than for FE
  - Current RODs were built by European collaborators, and considerable interest exists there
    for a similar role in Phase II
  - In any case, US groups are playing significant roles in Phase I LDPS, and will bring this
    expertise to planning of BE electronics for Phase II

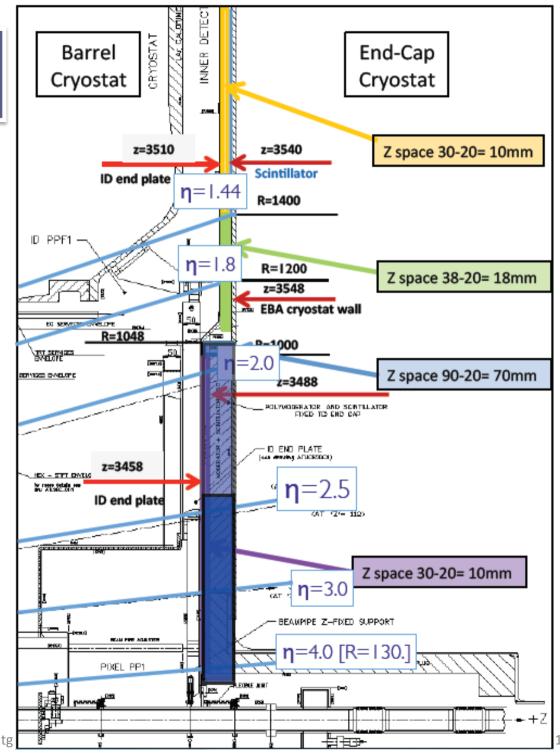


# Possible High-Granularity Timing Detector (HGTD)



### **HGTD**

- Scoping Document includes possible new "4D" detector in space of current MTBS
  - $\Delta z = 60 \text{ mm detector could}$ cover  $\eta$  of 2.4 - 4.1 (5.0)
- Aiming for time res'n of 30-50 ps and spatial granularity of 1-100 mm<sup>2</sup>
- Possibly multiple layers, if also used as preshower
- Synergy with possible Si/Cu miniFCAL (and also CMS)
- More MC studies needed to optimize design and evaluate ability to use timing to reject pileup, select PV, ...







Speakers: Ana Maria Henriques Correia (CERN), Francesco Lanni (Brookhaven National Laboratory (US))

the effect of the timing detector in association with the beam profile, vertex selection, other methods for forward pileup jet

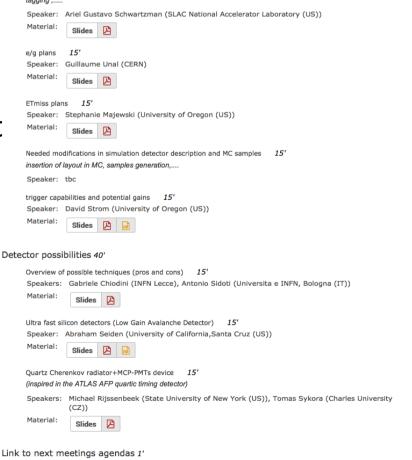
Performance potential gains of a timing/preshower device 45'

### **Timing Detector Organization**

First mtg was held on July 3/2015

https://indico.cern.ch/event/403701/

- Abe Seiden presented ideas about using ultra-fast Si detectors
- Known US interests so far include UCSC, Oregon, BNL
  16:05-16:45
- ATLAS has scheduled ~monthly mtgs to organize this new effort



July 13, 2015 Open Mtg link to 2015 agendas &

15:00 - 15:20

15:20 - 16:05

Introduction 201



### **US LAr Institutions**

- sFCAL (or MiniFCAL)
  - U Arizona
  - Interest from U Iowa
- Frontend Electronics Components
  - BNL, Columbia, U Penn, SMU, UT Dallas
  - Interest from UT Austin
- FEB2 and Frontend System Integration FEB2
  - BNL, Columbia
- Backend Electronics
  - U Arizona, U Oregon, Stony Brook, BNL
  - Interest from MSU
- Timing Detector
  - Interest from UCSC, Oregon, BNL



# **Summary (Part I)**

- US ATLAS is playing many critical roles in ongoing LAr Phase II planning
- ❖ FCAL upgrade option will be finalized around end of 2015. US plans to contribute in either sFCAL or miniFCAL scenarios
- Readout upgrade concentrates on FEB2 and US is leading the efforts. Current R&D centered on FE components and options that will influence the system integration. Decisions in the R&D course will guide the efforts to construction.
- There is also considerable US interest and expertise in the BE electronics. Discussions concerning BE responsibilities are less advanced so far (and will involve also TDAQ/LAr boundaries).
- ❖ A new issue is a possible HGTD, in which a few US institutes have already expressed interest.



# **Summary (Part II)**

- To prepare for DoE and NSF construction proposals (and corresponding CD-0 and CDR reviews), need to make rapid progress on scope, institutional responsibilities, costs, manpower, ...
- Any new institutes who are interested in participating should contact JP as soon as possible
- Proposals for technical contributions should be accompanied by scientific (ie. physicist) commitments
  - A great way to get started is to join the urgent simulation effort that is required (and VERY under-staffed) to evaluate the physics case for the upgrade, to optimize the designs, and to choose among the various options



# **Backup Slides**



# **Process for Developing Scope**

- U.S. Scope (deliverables) expressed in a WBS + Budget/Schedule
  - being developed by L2 Managers

WBS	System	L2 Manager
6.1	Pixels	P. Grenier (SLAC)
6.3	LAr	J. Parsons (Columbia)
6.5	Muons	T. Schwarz (Michigan)

WBS	System	L2 Manager
6.2	Strips	C. Haber (LBNL)
6.4	TileCal	M. Oreglia (Chicago)
6.6	TDAQ	E. Lipeles (Penn), J. Zhang (ANL)

- driven by expertise developed in the U.S. (reflected in R&D program)
- current status summarized on next slides

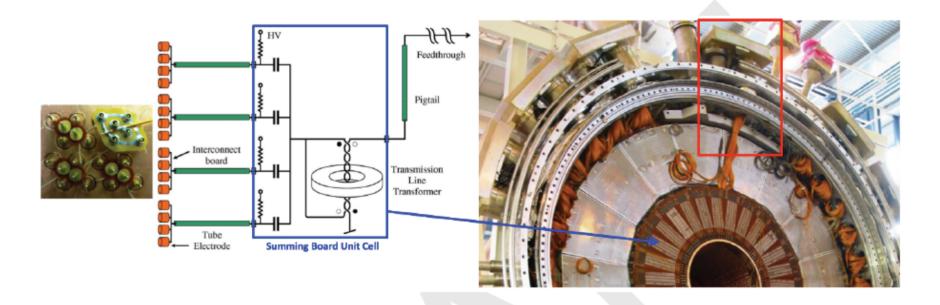
### Timeline for WBS/Budget/Schedule

Hal Evans' talk at US ATLAS Workshop

- Aug/Sep 2015: scrubbing of sub-system WBS/Budget/Schedule
- Oct 2015: snapshot "frozen" for CD-0/CDR
- 2016-18: further scope development for CD-1,2/3 / PDR/FDR
  - note that scope changes become more difficult with time
- end 2018: scope is fixed after CD-2/3 / FDR

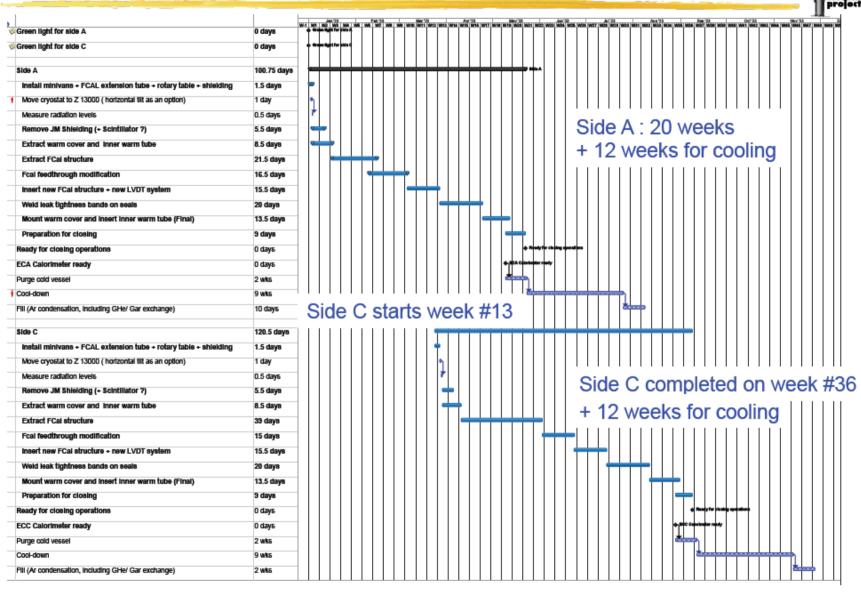
**Table 12.** Numbers of electrodes, interconnects and readout channels for the ATLAS FCal. For the high-granularity sFCal, the number of readout channels could be increased to the number of interconnects by removing a signal summing stage that is currently done on board in the cold volume of the endcap cryostat.

	Electrodes	Interconnects	Channels
FCal1	12,260	3066	1008
FCal2	10,200	1700	500
FCal3	8,224	914	254



**Figure 24.** This figure illustrates the summing of signals for the FCal1. On the left is a schematic of how the signals from four groups of electrodes are summed on boards located on the rear face of the HEC (seen on the right). Also visible on the right (highlighted) is the FCal signal feed-through serving the half-crate that is currently used for the FCal front-end electronics. The HV distribution is also performed on the summing boards, which carry the current-limiting protection resistors referred to in the text.

#### Installation time schedule



M. Raymond

LAr phase II Engineering - March 04th, 2015

#### sFCal Production schedule



Main milestones of the last sFCal production schedule (Sept. 2012)

sFCal R&D: Sept. 2011 - Feb. 2014

sFCal approval: Beginning 2015

sFCal1 production : Jan. 2015 → Apr. 2020

sFCal2 production : Nov. 2015 → Feb. 2020

sFCal3 production : Jan. 2016 → Oct. 2019

sFCal-A integration (at Cern) : Jan. 2018 → March 2020

sFCal-A beam calibration : May 2020 → Aug. 2020

sFCal-C integration (at Cern) : Jul. 2019 → May 2021

sFCal-C beam calibration : May 2021 → Aug.2021

Preparation for installation : Sept. 2021 → Dec. 2021

sFCal ready for installation in the cryostat (both): Beg. 2022

Some optimization is possible here for contingencies

Will High Granularity sFCal

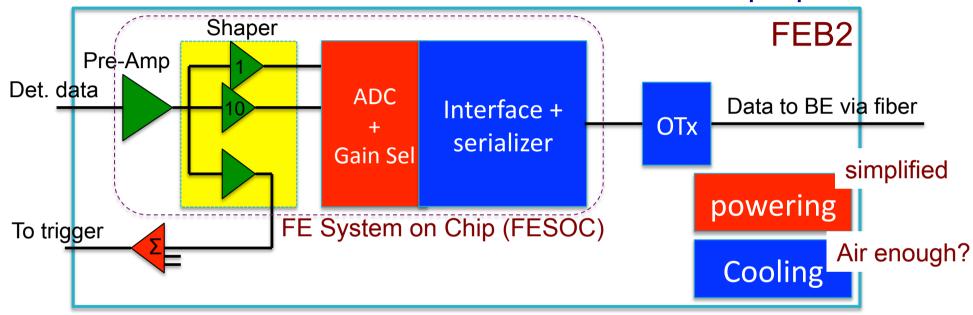
need more production time?

Providing the production can really start just after the approval, a decision by end of 2015 is still consistent with a status "ready for installation" by beg. 2023 but very close to be critical



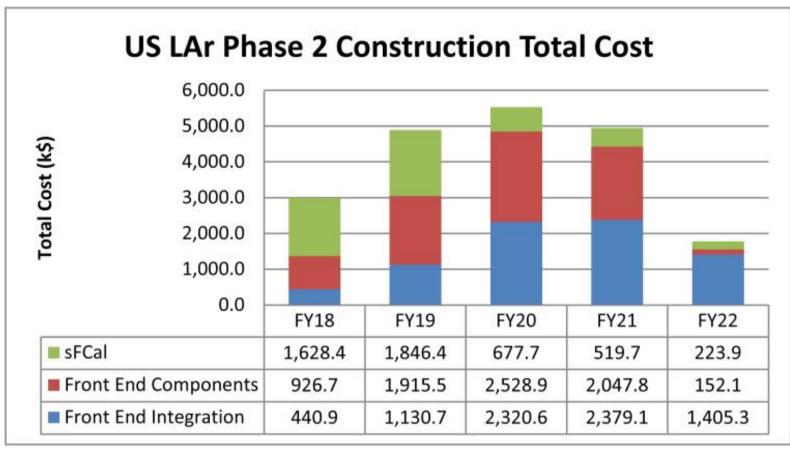
# FE System-on-Chip

### The idea has been around awhile but now it's a proposal



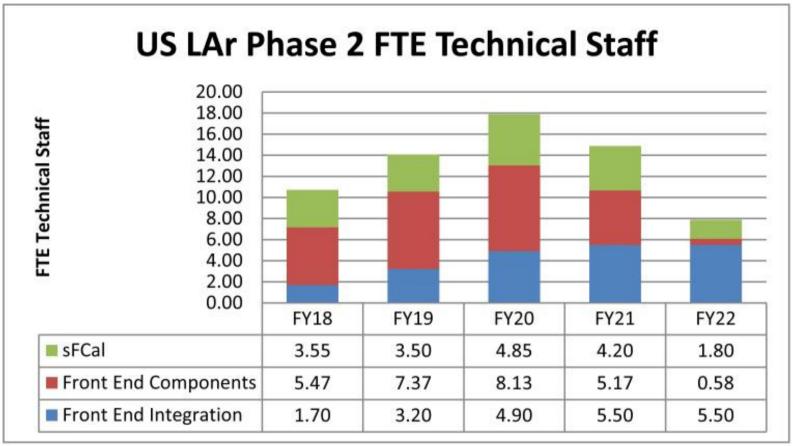
- FESOC, a one die or two die chip that integrates the three key ASICs. By combining the ADC with the serializer (both in 65 nm CMOS), one eliminates the output circuits for the ADC hence saves power.
- Impact on system integration and in construction:
  - Simplified FEB2, powering and possibly air (not water) cooling.
  - Reduce production cost in chip packaging and QA, and in FEB PCB.
  - The impact on yield may be small as the yield of 65 nm CMOS is expected to be high and the cost of die is small.





Item	Cost (k\$)
sFCal	4,896
Front End Components	7,571
Front End Integration	7,677
Total	20,144





Item	Tech FTE
sFCal	17.9
Front End Components	26.7
Front End Integration	20.8
Total	65.4